

| L Number | Hits | Search Text | DB | Time stamp |
|----------|-------|---|---|------------------|
| 15 | 0 | choos\$5 near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:41 |
| 36 | 0 | choice near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:43 |
| 43 | 1 | model near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:45 |
| 50 | 4628 | model near model | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:47 |
| 57 | 17 | (model near model) and inspection and wafer | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:47 |
| 64 | 363 | die near model | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:47 |
| 71 | 9 | (die near model) and inspection and wafer | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:47 |
| 22 | 6 | determin\$5 near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:49 |
| 29 | 1 | decid\$5 near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:50 |
| 78 | 902 | (reference or model) near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:51 |
| 85 | 13730 | compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:57 |
| 92 | 10117 | die near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:57 |
| 99 | 199 | ((reference or model) near die) and ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 13:04 |
| 106 | 58 | ((((reference or model) near die) and ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))) and wafer | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 13:04 |

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|-----|-----|---|---|------------------|
| 113 | 47 | ((reference or model) near die) same ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 13:04 |
| 120 | 23 | ((reference or model) same ((compar\$5 with (two or "2" or adjacent or neighbor\$5) near (chip or die or circuit)) or (die near die))) and wafer | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 13:04 |
| - | 5 | select\$5 near reference near die | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/05/21 12:41 |
| - | 1 | 2000-656045.NRAN. | DERWENT | 2003/05/20 14:42 |
| - | 507 | (382/145,149).CCLS. | USPAT | 2003/05/20 14:44 |
| - | 34 | (known or good or defect) with reference near die | USPAT | 2003/05/20 14:45 |
| - | 5 | (known or good or defect) near2 reference near die | USPAT | 2003/05/20 14:45 |
| - | 13 | ((382/145,149).CCLS.) and reference near die | USPAT | 2003/05/20 15:32 |
| - | 25 | ((known or good or defect) with reference near die) not ((382/145,149).CCLS.) and reference near die) | USPAT | 2003/05/20 15:32 |